

Search Notes

Application/Control No.

10/532,274

Examiner

Son T. Nguyen

Applicant(s)/Patent under
Reexamination

WASE ET AL.

Art Unit

3643

SEARCHED

Class	Subclass	Date	Examiner
119	14.08 14.43	4/15/2007	STN
	14.27		
	14.28		
	14.36		
	14.42		
	14.44		
	14.47		
	14.51		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IPC foreign search, see printouts	4/15/2007	STN
text search, see printouts	4/15/2007	STN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner